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FAST Products	

74F174

Flip-Flop

Hex D Flip-Flops

FEATURES

- Six edge-triggered D-type flip-flops
- Buffered common Clock
- Buffered, asynchronous Master Reset

DESCRIPTION

The 74F174 has six edge-triggered D-type flip-flops with individual D inputs and Q outputs. The common buffered Clock (CP) and Master Reset ($\overline{MR}$) inputs load and reset (clear) all flip-flops simultaneously.

The register is fully edge-triggered. The state of each D input, one setup time before the Low-to-High clock transition is transferred to the corresponding flip-flop's Q output.

All Q outputs will be forced Low independent of Clock or Data inputs by a Low voltage level on the $\overline{MR}$ input. The device is useful for applications where true outputs only are required, and the Clock and Master Reset are common to all storage elements.

TYPE	TYPICAL f_{MAX}	TYPICAL SUPPLY CURRENT (TOTAL)
74F174	100 MHz	35 mA

ORDERING INFORMATION

PACKAGES	COMMERCIAL RANGE $V_{CC} = 5V \pm 10\%$; $T_A = 0^\circ C$ to $+70^\circ C$
16-Pin Plastic DIP	N74F174N
16-Pin Plastic SO	N74F174D

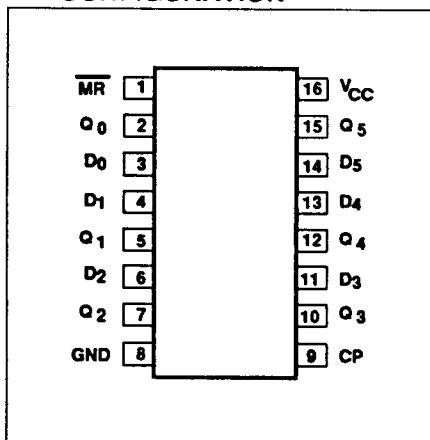
INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

PINS	DESCRIPTION	74ALS(U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
$D_0 - D_5$	Data inputs	1.0/1.0	20 μ A/0.6mA
CP	Clock Pulse input (active rising edge)	1.0/1.0	20 μ A/0.6mA
$\overline{MR}$	Master Reset input (active-Low)	1.0/1.0	20 μ A/0.6mA
$Q_0 - Q_5$	Outputs	50/33	1.0mA/20mA

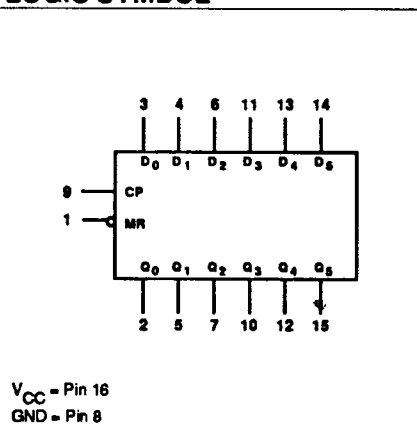
NOTE:

One (1.0) FAST Unit Load is defined as: 20 μ A in the High state and 0.6mA in the Low state.

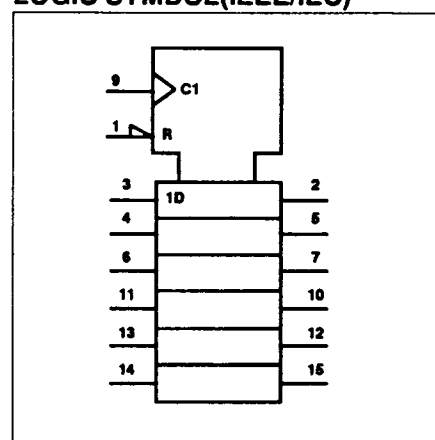
PIN CONFIGURATION



LOGIC SYMBOL



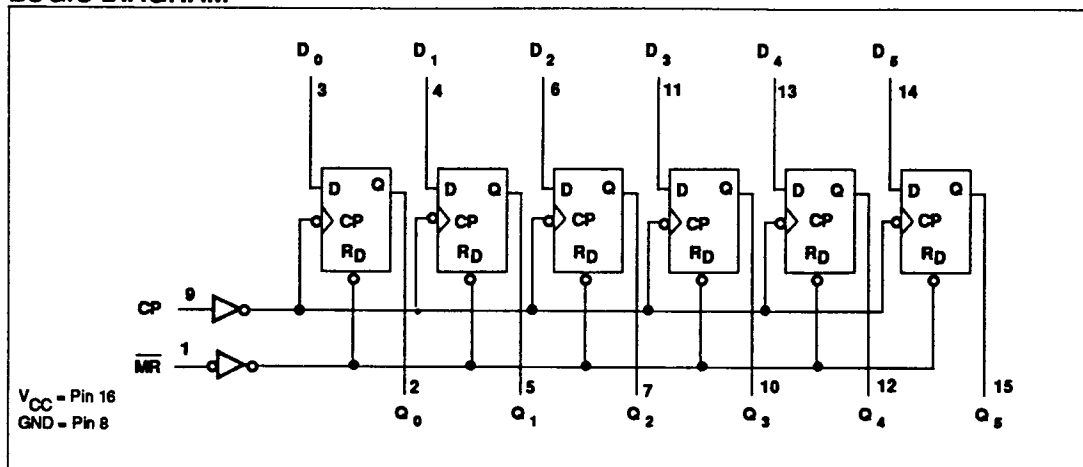
LOGIC SYMBOL (IEEE/IEC)



Flip-Flop

FAST 74F174

LOGIC DIAGRAM



FUNCTION TABLE

I INPUTS			OUTPUTS	OPERATING MODE
$\overline{MR}$	CP	D	Q_n	
L	X	X	L	Reset (clear) Load "1" Load "0"
H	$\uparrow$	h	H	
H	$\uparrow$	l	L	

H = High voltage level

L = Low voltage level

X = Don't care

 $\uparrow$ = Low-to-High Clock transition

h = High voltage level one set-up time prior to the Low-to-High Clock transition.

l = Low voltage level one set-up time prior to the Low-to-High Clock transition.

ABSOLUTE MAXIMUM RATINGS (Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V_{CC}	Supply voltage	-0.5 to +7.0	V
V_{IN}	Input voltage	-0.5 to +7.0	V
I_{IN}	Input current	-30 to +5	mA
V_{OUT}	Voltage applied to output in High output state	-0.5 to + V_{CC}	V
I_{OUT}	Current applied to output in Low output state	40	mA
T_A	Operating free-air temperature range	0 to +70	°C
T_{STG}	Storage temperature	-65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS			UNIT
		Min	Nom	Max	
V_{CC}	Supply voltage	4.5	5.0	5.5	V
V_H	High-level input voltage	2.0			V
V_L	Low-level input voltage			0.8	V
I_{IK}	Input clamp current			-18	mA
I_{OH}	High-level output current			-1	mA
I_{OL}	Low-level output current			20	mA
T_A	Operating free-air temperature range	0		70	°C

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DC ELECTRICAL CHARACTERISTICS (Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER	TEST CONDITIONS ¹		LIMITS			UNIT
				Min	Typ ²	Max	
V _{OH}	High-level output voltage	V _{CC} = MIN, V _{IL} = MAX	±10%V _{CC}	2.5			V
		V _{IH} = MIN, I _{OH} = MAX	±5%V _{CC}	2.7	3.4		V
V _{OL}	Low-level output voltage	V _{CC} = MIN, V _{IL} = MAX	±10%V _{CC}		0.30	0.50	V
		V _{IH} = MIN, I _{OL} = MAX	±5%V _{CC}		0.30	0.50	V
V _{IK}	Input clamp voltage	V _{CC} = MIN, I _I = I _{IK}			-0.73	-1.2	V
I _I	Input current at maximum input voltage	V _{CC} = MAX, V _I = 7.0V				100	μA
I _{IH}	High-level input current	V _{CC} = MAX, V _I = 2.7V				20	μA
I _{IL}	Low-level input current	V _{CC} = MAX, V _I = 0.5V				-0.6	mA
I _{OS}	Short circuit output current ³	V _{CC} = MAX		-60		-150	mA
I _{CC}	Supply current (total)	V _{CC} = MAX, D _n = $\overline{\text{MR}}$ = 4.5V, CP = ↑			35	45	mA

NOTES:

- For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
- All typical values are at $V_{CC} = 5\text{V}$, $T_A = 25^\circ\text{C}$.
- Not more than one output should be shorted at a time. For testing I_{OS} , the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter test, I_{OS} tests should be performed last.

AC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITION	LIMITS					UNIT
			$T_A = +25^{\circ}\text{C}$ $V_{CC} = 5\text{V}$ $C_L = 50\text{pF}$ $R_L = 500\Omega$			$T_A = 0^{\circ}\text{C to } +70^{\circ}\text{C}$ $V_{CC} = 5\text{V} \pm 10\%$ $C_L = 50\text{pF}$ $R_L = 500\Omega$		
			Min	Typ	Max	Min	Max	
f_{MAX}	Maximum clock frequency	Waveform 1	80	100		80		MHz
t_{PLH} t_{PHL}	Propagation delay CP to Q_n	Waveform 1	3.5 4.5	5.5 6.0	8.0 10.0	3.5 4.5	9.0 11.0	ns
t_{PHL}	Propagation delay $\overline{\text{MR}}$ to Q_n	Waveform 2	5.0	8.5	14.0	5.0	15.0	ns

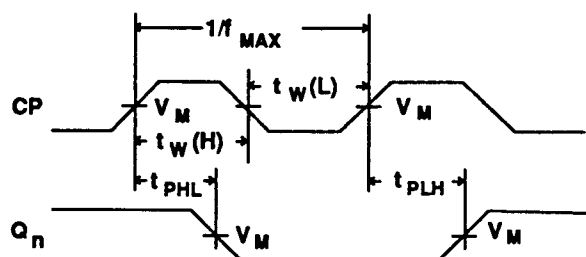
AC SETUP REQUIREMENTS

SYMBOL	PARAMETER	TEST CONDITION	LIMITS					UNIT
			$T_A = +25^{\circ}\text{C}$ $V_{CC} = 5\text{V}$ $C_L = 50\text{pF}$ $R_L = 500\Omega$			$T_A = 0^{\circ}\text{C to } +70^{\circ}\text{C}$ $V_{CC} = 5\text{V} \pm 10\%$ $C_L = 50\text{pF}$ $R_L = 500\Omega$		
			Min	Typ	Max	Min	Max	
$t_s(\text{H})$ $t_s(\text{L})$	Setup time, High or Low D_n to CP	Waveform 3	4.0 4.0			4.0 4.0		ns
$t_h(\text{H})$ $t_h(\text{L})$	Hold time, High or Low D_n to CP	Waveform 3	0 0			0 0		ns
$t_w(\text{H})$ $t_w(\text{L})$	CP Pulse width, High or Low	Waveform 1	4.0 6.0			4.0 6.0		ns
$t_w(\text{L})$	$\overline{\text{MR}}$ Pulse width, Low	Waveform 2	5.0			5.0		ns
t_{REC}	Recovery time, $\overline{\text{MR}}$ to CP	Waveform 2	5.0			5.0		ns

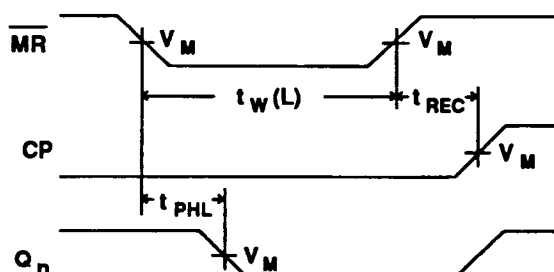
Flip-Flop

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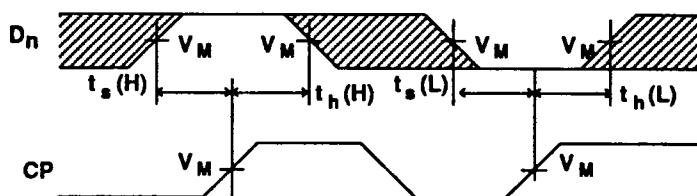
AC WAVEFORM



Waveform 1. Propagation Delay, Clock Input To Output, Clock Pulse Width, and Maximum Clock Frequency



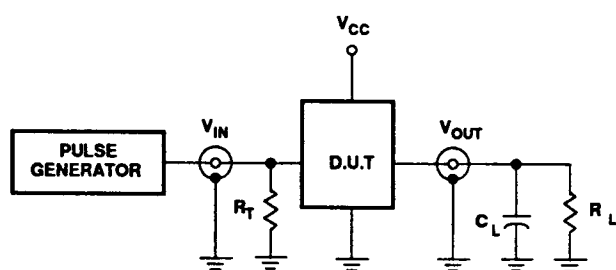
Waveform 2. Master Reset Pulse Width, Master Reset to Output Delay and Master Reset to Clock Recovery Time



Waveform 3. Data Setup And Hold Times

NOTE: For all waveforms, $V_M = 1.5V$.
The shaded areas indicate when the input is permitted to change for predictable output performance.

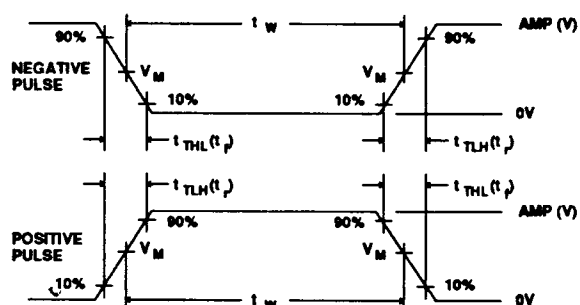
TEST CIRCUIT AND WAVEFORMS



Test Circuit For Totem-Pole Outputs

DEFINITIONS

- R_L = Load resistor; see AC CHARACTERISTICS for value.
- C_L = Load capacitance includes jig and probe capacitance; see AC CHARACTERISTICS for value.
- R_T = Termination resistance should be equal to Z_{OUT} of pulse generators.



$V_M = 1.5V$
Input Pulse Definition

FAMILY	INPUT PULSE REQUIREMENTS				
	Amplitude	Rep. Rate	t_W	t_{TLH}	t_{THL}
74F	3.0V	1MHz	500ns	2.5ns	2.5ns